

#### **Table 1: General Features**

Туре	$v_{\text{DSS}}$	R <sub>DS(on)</sub>	ID	Pw
STB200NF04 STB200NF04-1 STP200NF04	40 V 40 V 40 V	< 0.0037 Ω < 0.0037 Ω < 0.0037 Ω	-	310 W

- STANDARD THRESHOLD DRIVE
- 100% AVALANCHE TESTED

# DESCRIPTION

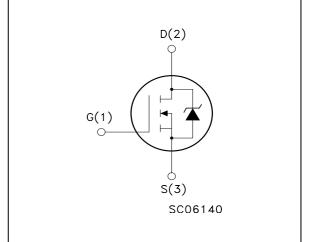
This MOSFET is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalance characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

#### **APPLICATIONS**

- HIGH CURRENT, HIGH SWITCHING SPEED
- AUTOMOTIVE

Figure 1: Package

Figure 2: Internal Schematic Diagram



#### **Table 2: Order Codes**

SALES TYPE	MARKING	PACKAGE	PACKAGING
STB200NF04T4	B200NF04	D <sup>2</sup> PAK	TAPE & REEL
STB200NF04-1	B200NF04	I <sup>2</sup> PAK	TUBE
STP200NF04	P200NF04	TO-220	TUBE

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# STP200NF04 - STB200NF04 - STB200NF04-1

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	40	V
V <sub>DGR</sub>	Drain-gate Voltage ( $R_{GS}$ = 20 k $\Omega$ )	40	V
V <sub>GS</sub>	Gate- source Voltage	± 20	V
I <sub>D</sub> (#)	Drain Current (continuos) at T <sub>C</sub> = 25°C	120	A
I <sub>D</sub> (#)	Drain Current (continuos) at T <sub>C</sub> = 100°C	120	A
$I_{DM}(\bullet)$	Drain Current (pulsed)	480	A
Ртот	Total Dissipation at $T_C = 25^{\circ}C$	310	W
	Derating Factor	2.07	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	1.5	V/ns
E <sub>AS</sub> (2)	Single Pulse Avalanche Energy	1.3	J
T <sub>j</sub> T <sub>stg</sub>	Operating Junction Temperature Storage Temperature	-55 to 175	°C

#### **Table 3: Absolute Maximum ratings**

(•) Pulse width limited by safe operating area (1)  $I_{SD} \le 120A$ ,  $di/dt \le 500A/\mu s$ ,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_j \le T_{JMAX}$ . (2) Starting  $T_j = 25^{\circ}C$ ,  $I_d = 60A$ ,  $V_{DD}=30$  V (#) Current Limited by Package

#### **Table 4: Thermal Data**

		TO-220 / I <sup>2</sup> PAK / D <sup>2</sup> PAK	
Rthj-case	Thermal Resistance Junction-case Max	0.48	°C/W
Rthj-pcb	Thermal Resistance Junction-pcb Max	(see Figure 17)	°C/W
Rthj-amb	Thermal Resistance Junction-ambient (Free air) Max	62.5	°C/W
ΤI	Maximum Lead Temperature For Soldering Purpose	300	°C

# ELECTRICAL CHARACTERISTICS (T<sub>CASE</sub> =25°C UNLESS OTHERWISE SPECIFIED) Table 5: On/Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	40			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating V <sub>DS</sub> = Max Rating, T <sub>C</sub> = 125 °C			1 10	μΑ μΑ
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 20V$			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2		4	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 90 A		3.3	3.7	mΩ

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# **ELECTRICAL CHARACTERISTICS (CONTINUED)**

## Table 6: Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (1)	Forward Transconductance	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 90 A		150		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>DS</sub> = 25V, f = 1 MHz, V <sub>GS</sub> = 0		5100 1600 600		pF pF pF

# Table 7: Switching On/Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$\label{eq:VD} \begin{array}{l} V_{DD} = 20 \ V, \ I_D = 90 \ A \\ R_G = 4.7 \Omega \ V_{GS} = 10 \ V \\ (see \ Figure \ 20) \end{array}$		30 320 140 120		ns ns ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 20V, I_D = 120 \text{ A}, \\ V_{GS} = 10V \\ (see Figure 23)$		170 30 62	210	nC nC nC

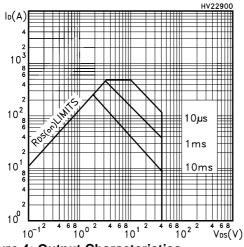
## **Table 8: Source Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (2)	Source-drain Current Source-drain Current (pulsed)				120 480	A A
V <sub>SD</sub> (1)	Forward On Voltage	I <sub>SD</sub> = 120 A, V <sub>GS</sub> = 0			1.3	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD}$ = 120 A, di/dt = 100A/µs V <sub>DD</sub> = 30V, T <sub>j</sub> = 150°C (see Figure 21)		85 190 4.5		ns nC A

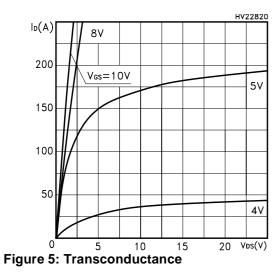
Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
Pulse width limited by safe operating area.



Figure 3: Safe Operating Area



**Figure 4: Output Characteristics** 



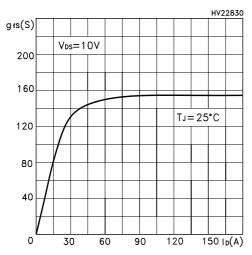


Figure 6: Thermal Impedance

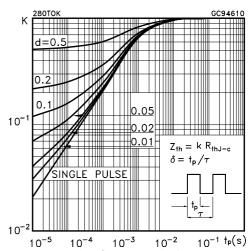
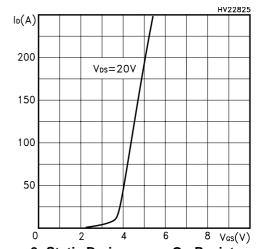
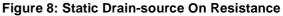


Figure 7: Transfer Characteristics





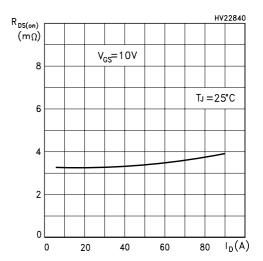


Figure 9: Gate Charge vs Gate-source Voltage

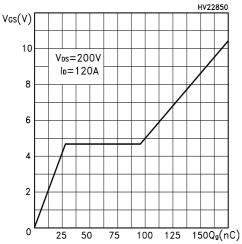


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

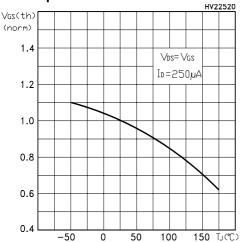
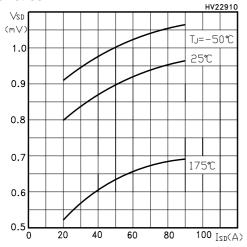


Figure 11: Dource-Drain Diode Forward Characteristics



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#### Figure 12: Capacitance Variations

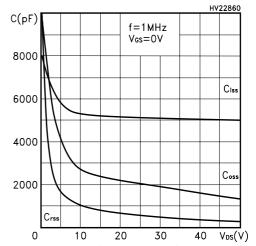


Figure 13: Normalized On Resistance vs Temperature

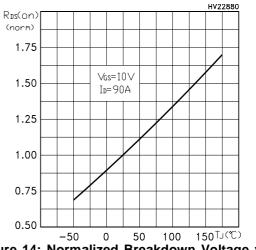


Figure 14: Normalized Breakdown Voltage vs Temperature

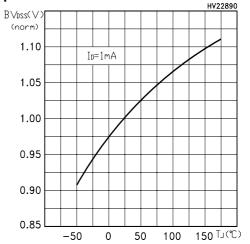


Figure 15: Thermal Resistance Rthj-a vs PCB Copper Area

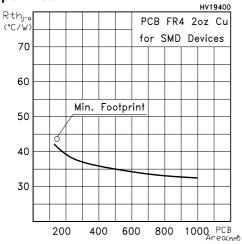


Figure 16: Max Power Dissipation vs PCB Copper Area

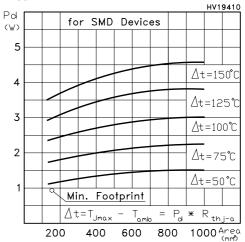
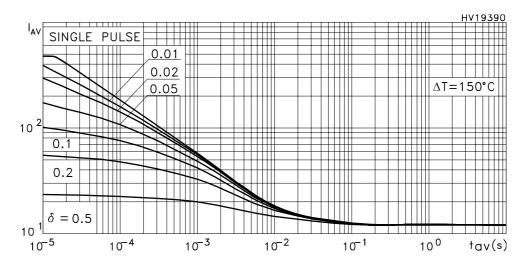




Figure 17: Allowable lav vs. Time in Avalanche



The previous curve gives the safe operating area for unclamped inductive loads, single pulse or repetitive, under the following conditions:

$$\begin{split} & \mathsf{P}_{\mathsf{D}(\mathsf{A}\mathsf{V}\mathsf{E})} = 0.5 \,^* \, (1.3 \,^* \mathsf{B}\mathsf{V}_{\mathsf{D}\mathsf{S}\mathsf{S}} \,^* \, \mathsf{I}_{\mathsf{A}\mathsf{V}}) \\ & \mathsf{E}_{\mathsf{A}\mathsf{S}(\mathsf{A}\mathsf{R})} = \mathsf{P}_{\mathsf{D}(\mathsf{A}\mathsf{V}\mathsf{E})} \,^* \, \mathsf{t}_{\mathsf{A}\mathsf{V}} \end{split}$$

## Where:

Where:

 $I_{AV}$  is the Allowable Current in Avalanche  $P_{D(AVE)}$  is the Average Power Dissipation in Avalanche (Single Pulse)  $t_{AV}$  is the Time in Avalanche

To derate above 25 °C, at fixed I<sub>AV</sub>, the following equation must be applied:

 $I_{AV} = 2 * (T_{jmax} - T_{CASE}) / (1.3 * BV_{DSS} * Z_{th})$ 

 $Z_{th} = K * R_{th}$  is the value coming from Normalized Thermal Response at fixed pulse width equal to  $T_{AV}$ .

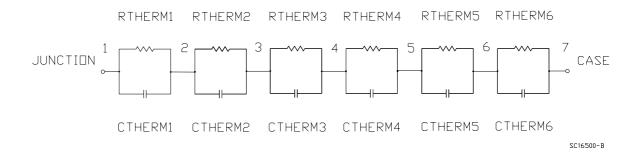


# SPICE THERMAL MODEL

#### Table 9: 6th Order RC Network

Parameter	Node	Value
CTHERM1	1 - 2	1.4958E-3
CTHERM2	2 - 3	3.5074E-2
CTHERM3	3 - 4	5.939E-2
CTHERM4	4 - 5	9.7411E-2
CTHERM5	5 - 6	8.8596E-2
CTHERM6	6 - 7	8.2755E-1
RTHERM1	1 - 2	0.0384
RTHERM2	2 - 3	0.0624
RTHERM3	3 - 4	0.072
RTHERM4	4 - 5	0.0912
RTHERM5	5 - 6	0.1008
RTHERM6	6 - 7	0.1152

#### Figure 18: Schematic of 6th Order RC Network



# Figure 19: Unclamped Inductive Load Test Circuit

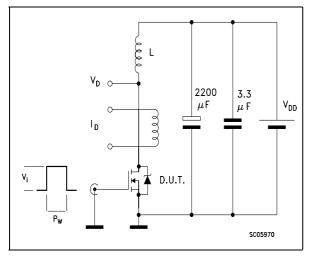


Figure 20: Switching Times Test Circuit For Resistive Load

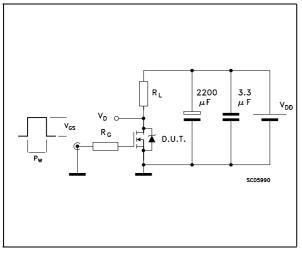
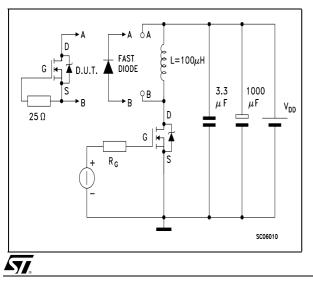


Figure 21: Test Circuit For Inductive Load Switching and Diode Recovery Times



# Figure 22: Unclamped Inductive Wafeform

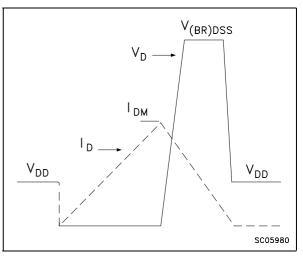
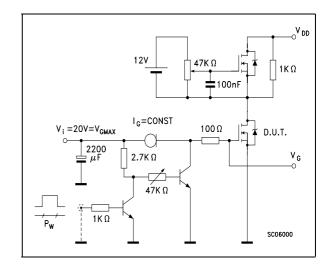
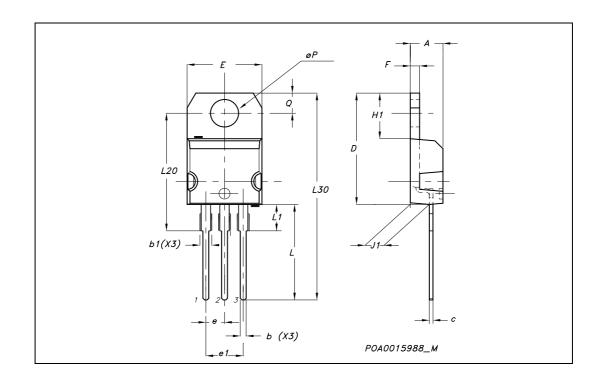


Figure 23: Gate Charge Test Circuit



DIM.		mm.			inch	
	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
Е	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116

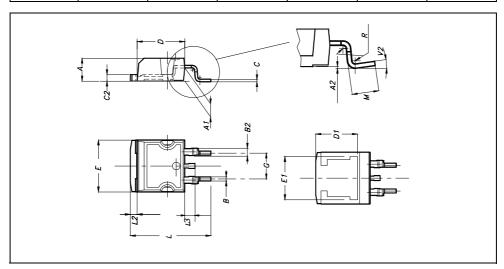




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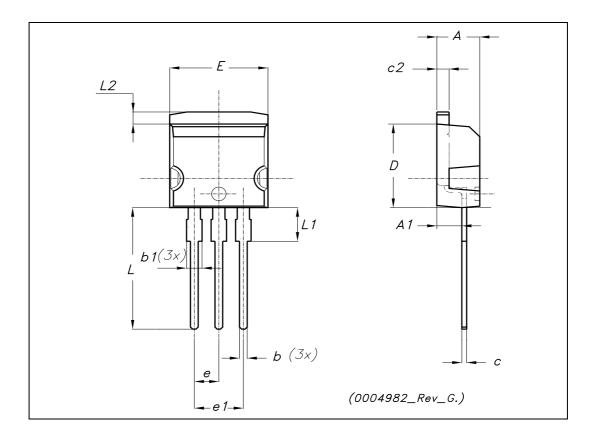
DIM.		mm.			inch	
DIN.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
А	4.4		4.6	0.173		0.181
A1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
В	0.7		0.93	0.027		0.036
B2	1.14		1.7	0.044		0.067
С	0.45		0.6	0.017		0.023
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1		8			0.315	
E	10		10.4	0.393		
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.590		0.625
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.068
М	2.4		3.2	0.094		0.126
R		0.4			0.015	
V2	0°		4°	T		

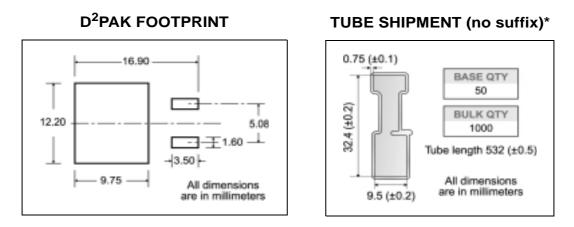
# D<sup>2</sup>PAK MECHANICAL DATA



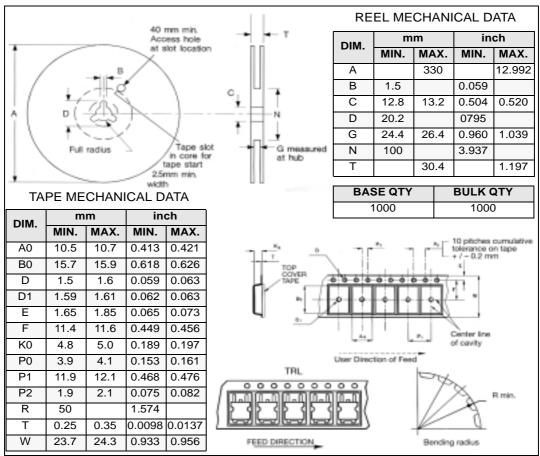
DIM		mm.			inch		
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
А	4.40		4.60	0.173		0.181	
A1	2.40		2.72	0.094		0.107	
b	0.61		0.88	0.024		0.034	
b1	1.14		1.70	0.044		0.066	
С	0.49		0.70	0.019		0.027	
c2	1.23		1.32	0.048		0.052	
D	8.95		9.35	0.352		0.368	
е	2.40		2.70	0.094		0.106	
e1	4.95		5.15	0.194		0.202	
Е	10		10.40	0.393		0.410	
L	13		14	0.511		0.551	
L1	3.50		3.93	0.137		0.154	
L2	1.27		1.40	0.050		0.055	

TO-262 (I<sup>2</sup>PAK) MECHANICAL DATA









\* on sales type

# STP200NF04 - STB200NF04 - STB200NF04-1

# Table 10: Revision History

Date	Revision	Description of Changes
28-Sep-2004	2	New Stylesheet. No Content Change
11-Oct-2004	3	Final datasheet



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